International Rectifier

- Logic-Level Gate Drive
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- · Lead-Free

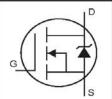
Description

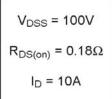
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

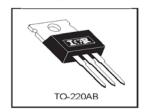
The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

IRL520NPbF









Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	10		
I _D @ T _C = 100°C	Continuous Drain Current, VGS @ 10V	7.1	Α	
I _{DM}	Pulsed Drain Current ①	35		
P _D @T _C = 25°C	Power Dissipation	48	W	
	Linear Derating Factor	0.32	W/°C	
V _{GS}	Gate-to-Source Voltage	± 16	V	
E _{AS}	Single Pulse Avalanche Energy②	85	mJ	
I _{AR}	Avalanche Current①	6.0	A	
E _{AR}	Repetitive Avalanche Energy①	4.8	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
ReJC	Junction-to-Case		3.1	
R _{ecs}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
R ₀ JA	Junction-to-Ambient		62	

Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	100			٧	$V_{GS} = 0V, I_{D} = 250 \mu A$
Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance			0.18	Ω	V _{GS} = 10V, I _D = 6.0A ④
		_	0.22		V _{GS} = 5.0V, I _D = 6.0A ④
			0.26		V _{GS} = 4.0V, I _D = 5.0A ④
Gate Threshold Voltage	1.0		2.0	٧	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
Forward Transconductance	3.1			S	V _{DS} = 25V, I _D = 6.0A
Projects Course Leadings Courset			25		V _{DS} = 100V, V _{GS} = 0V
Drain-to-Source Leakage Current			250	μA	V _{DS} = 80V, V _{GS} = 0V, T _J = 150°C
Gate-to-Source Forward Leakage			100	A	V _{GS} = 16V
Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -16V
Total Gate Charge			20		I _D = 6.0A
Gate-to-Source Charge			4.6	nC	V _{DS} = 80V
Gate-to-Drain ("Miller") Charge			10		V _{GS} = 5.0V, See Fig. 6 and 13 ④
Turn-On Delay Time		4.0			V _{DD} = 50V
Rise Time		35			I _D = 6.0A
Turn-Off Delay Time		23		115	R_{G} = 11 Ω , V_{GS} = 5.0 V
Fall Time		22			$R_D = 8.2\Omega$, See Fig. 10 ④
Internal Drain Inductance		4.5		nΗ	Between lead,
					6mm (0.25in.)
Internal Source Inductance		7.5	_		from package
					and center of die contact
Input Capacitance		440			V _{GS} = 0V
Output Capacitance		97		pF	V _{DS} = 25V
Reverse Transfer Capacitance		50			f = 1.0MHz, See Fig. 5
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 100 — Breakdown Voltage Temp. Coefficient — 0.11 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage 1.0 — Forward Transconductance 3.1 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 4.0 Rise Time — 35 Turn-Off Delay Time — 23 Fall Time — 22 Internal Drain Inductance — 4.5 Internal Source Inductance — 440 Output Capacitance — 97	Drain-to-Source Breakdown Voltage 100 — — — Breakdown Voltage Temp. Coefficient — 0.11 — — 0.18 Static Drain-to-Source On-Resistance — — 0.22 — 0.26 Gate Threshold Voltage 1.0 — 2.0 Forward Transconductance 3.1 — — Drain-to-Source Leakage Current — — 25 Gate-to-Source Forward Leakage — — 100 Gate-to-Source Reverse Leakage — — 100 Total Gate Charge — — 4.6 Gate-to-Source Charge — — 4.6 Gate-to-Drain ("Miller") Charge — — 4.6 Gate-to-Drain ("Miller") Charge — — 4.5 Turn-Off Delay Time — 23 — Fall Time — 22 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 440 — </td <td>Drain-to-Source Breakdown Voltage 100 — — V Breakdown Voltage Temp. Coefficient — 0.11 — V/°C Static Drain-to-Source On-Resistance — — 0.22 Ω Gate Threshold Voltage 1.0 — 2.0 V Forward Transconductance 3.1 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Forward Leakage — — 100 nA Total Gate Charge — — 100 nA Gate-to-Source Reverse Leakage — — 4.6 nC Gate-to-Source Charge — — 4.6 nC Gate-to-Source Charge — — 4.0 — Gate-to-Drain ("Miller") Charge — 10 — Turn-On Delay Time — 35 — ns Fall Time —</td>	Drain-to-Source Breakdown Voltage 100 — — V Breakdown Voltage Temp. Coefficient — 0.11 — V/°C Static Drain-to-Source On-Resistance — — 0.22 Ω Gate Threshold Voltage 1.0 — 2.0 V Forward Transconductance 3.1 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Forward Leakage — — 100 nA Total Gate Charge — — 100 nA Gate-to-Source Reverse Leakage — — 4.6 nC Gate-to-Source Charge — — 4.6 nC Gate-to-Source Charge — — 4.0 — Gate-to-Drain ("Miller") Charge — 10 — Turn-On Delay Time — 35 — ns Fall Time —

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		4/	10		MOSFET symbol
	(Body Diode)		10	10 A	showing the	
I _{SM}	Pulsed Source Current			25		integral reverse ∘√ 🗂 🕈
	(Body Diode) ①⑥		—— 35	35	p-n junction diode.	
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 6.0A, V _{GS} = 0V ④
trr	Reverse Recovery Time		110	160	ns	T _J = 25°C, I _F =6.0A
Q _{IT}	Reverse RecoveryCharge		410	620	nC	di/dt = 100A/µs ④
ton	Forward Turn-On Time	urn-On Time Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}\text{C}$, L = 4.7mH $R_G = 25\Omega$, $I_{AS} = 6.0\text{A}$. (See Figure 12)
- $\label{eq:loss_loss} \begin{array}{l} \text{ } \\ \text$
- 9 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

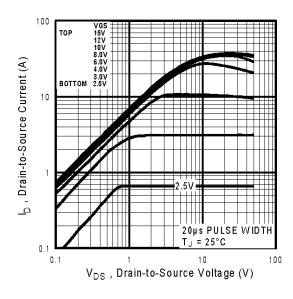


Fig 1. Typical Output Characteristics

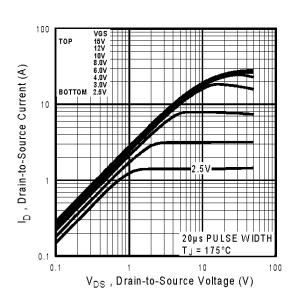


Fig 2. Typical Output Characteristics

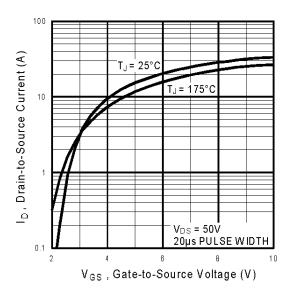


Fig 3. Typical Transfer Characteristics

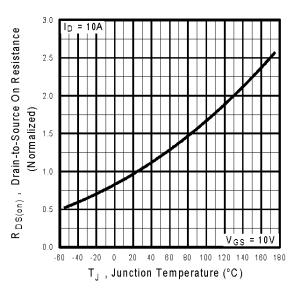


Fig 4. Normalized On-Resistance Vs. Temperature

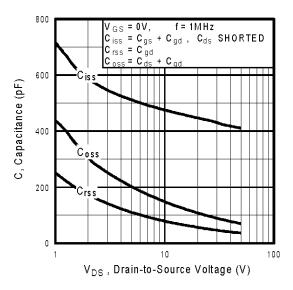


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

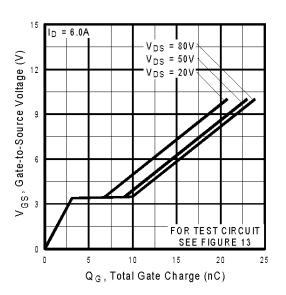


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

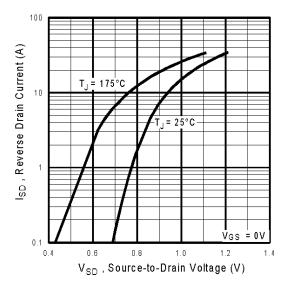


Fig 7. Typical Source-Drain Diode Forward Voltage

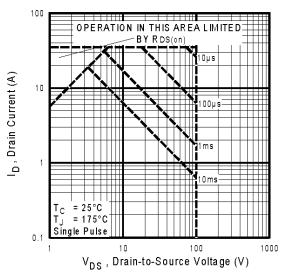


Fig 8. Maximum Safe Operating Area

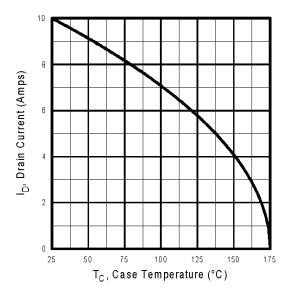


Fig 9. Maximum Drain Current Vs. Case Temperature

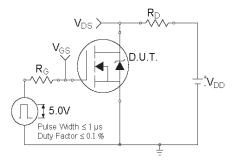


Fig 10a. Switching Time Test Circuit

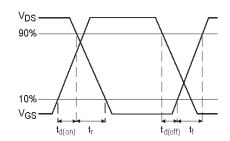
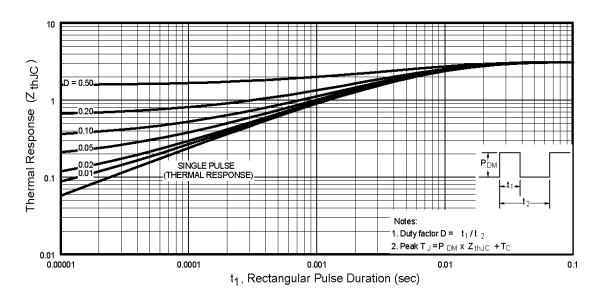


Fig 10b. Switching Time Waveforms



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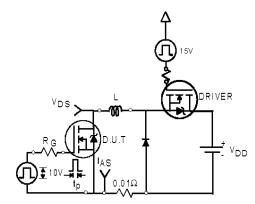


Fig 12a. Unclamped Inductive Test Circuit

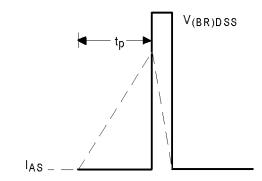


Fig 12b. Unclamped Inductive Waveforms

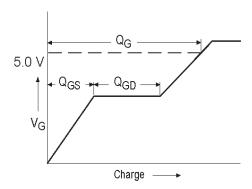


Fig 13a. Basic Gate Charge Waveform

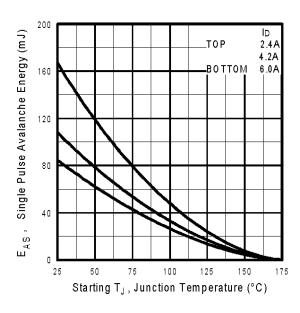


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

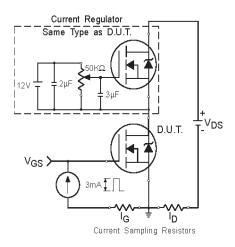
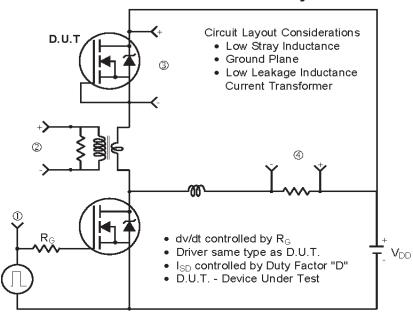


Fig 13b. Gate Charge Test Circuit www.irf.com

Peak Diode Recovery dv/dt Test Circuit



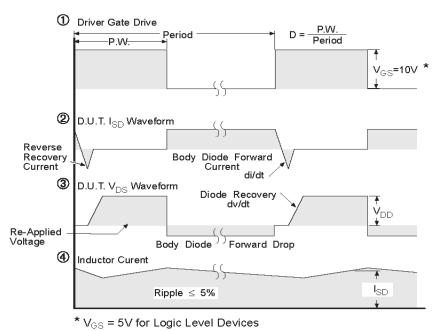
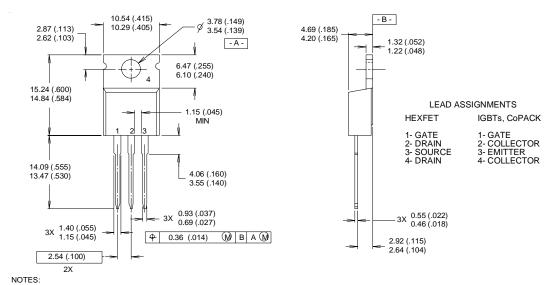


Fig 14. For N-Channel HEXFETS

International TOR Rectifier

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION: INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

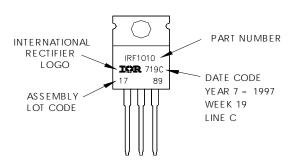
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



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